


<b>Search Notes</b>  	<b>Application/Control No.</b>  10762814	<b>Applicant(s)/Patent Under Reexamination</b>  BAU, DAVID
	<b>Examiner</b>  Qing Chen	<b>Art Unit</b>  2191

SEARCHED			
Class	Subclass	Date	Examiner
717	100,114-123	10/2/2009	/QC/

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) -- See Search History Printout	10/2/2009	/QC/
717/100,114-123 (limited class search)	10/2/2009	/QC/
Updated EAST Inventor Name Search and Assignee Search (US-PGPUB; USPAT) -- See Search History Printout	10/2/2009	/QC/
NPL Search (ACM; Google; Google Scholar) -- See Printout	10/2/2009	/QC/
Updated PALM Inventor Name Search	10/6/2009	/QC/
Consulted SPE Wei Zhen (AU 2191)	10/5/2009	/QC/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
717	100,114-123	10/6/2009	/QC/

--	--